## Application/Control No. Applicant(s)/Patent Under Reexamination 09/747,370 LABARGE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 1764 Hien Tran **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 422/180 04-2002 Deeba et al. US-6,375,910 Α US-В US-С D US-Ε US-US-F US-G US-Н 1 US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Date Document Number Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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